

Supplementary Information for:

A copper-containing oxytelluride as a promising thermoelectric material for waste heat recovery

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1. Experimental Details

a) Synthesis of $\text{Bi}_{1-x}\text{Pb}_x\text{OCuTe}$

Stoichiometric mixtures of Cu, Te, Bi, $\alpha\text{-Bi}_2\text{O}_3$ and PbO_2 were finely ground prior to be sealed in evacuated silica tubes (10^{-4} torr). Each mixture was first heated up to 350°C with a ramp rate of 1°C min^{-1} . After 24 hours, the temperature was increased to 500°C , and the silica tube maintained at that temperature for 48 hours. After slowly cooling down the tube to room temperature, each sample was ground and sealed in an evacuated silica tube again for a final firing at 500°C for 72 hours. All samples are of high purity, and contain only trace amounts of Bi_2O_3 or Bi_2TeO_5 . For electronic and thermal transport measurements, the as-prepared powders were hot pressed into well-densified pellets ($\sim 95\%$ of theoretical density), at 773 K and 50 bar for 30 minutes under a N_2 flow. X-ray diffraction data collected on the hot-pressed pellets is consistent with the absence of texture, indicating that grains are randomly oriented.

b) Structural characterization

Samples were analysed by powder X-ray diffraction using a Bruker D8 Advance Powder X-ray diffractometer, operating with germanium monochromated $\text{CuK}\alpha_1$ radiation ($\lambda = 1.54046 \text{ \AA}$) and fitted with a LynxEye detector. Data were collected over a range of $5 \leq 2\theta/^\circ \leq 120$ for a period of 10 hours. Rietveld refinements were carried out using the GSAS software.¹ The initial structural model was that of BiOCuTe , reported by Hiramatsu *et al.*²

c) Physical properties

Thermogravimetric analysis

Thermogravimetric analysis was performed using a DuPont Instruments 951 thermal analyser. Approximately 20 mg of finely ground crystals was heated under a flow of O_2 or N_2 over the temperature range $30 \leq T/^\circ\text{C} \leq 600$ using a heating rate of 5°C min^{-1} .

Low temperature electrical conductivity

The electrical conductivity of the sample as a function of temperature was measured using a 4-probe DC technique. An ingot ($\sim 10 \times 4 \times 1 \text{ mm}^3$) was cut from a hot-pressed pellet, four $50 \mu\text{m}$ silver wires were attached using colloidal silver paint and connections were made to a Keithley 2182 nanovoltmeter and a TTI QL564P power supply. The sample was mounted in an Oxford Instruments CF1200 cryostat connected to an ITC502 temperature controller. Measurements were carried out over the temperature range $100 \leq T/\text{K} \leq 350$.

Low temperature Seebeck coefficient

Measurements of the Seebeck coefficient in 5K steps over the temperature range $100 \leq T/\text{K} \leq 300$ were made on ingots (ca. $7 \times 3 \times 1 \text{ mm}^3$) cut from hot-pressed pellets. Each sample ingot was mounted on a copper holder, which incorporates a small heater (120Ω strain gauge) located close to one end of the sample. The copper holder is attached to the hot stage of a closed-cycle refrigerator (DE-202, Advanced Research Systems), which is connected to a Lakeshore LS-331 temperature controller. Two $50 \mu\text{m}$ copper wires were attached to the ends of the sample using silver paint and connections made to a Keithley 2182A nanovoltmeter. Two Au: 0.07% Fe vs. chromel thermocouples were placed at the hot and cold ends, and connected to a second Lakeshore LS-331 temperature controller.

¹ A.C. Larson and R.B. von Dreele, General Structure Analysis System, Los Alamos Laboratory, 1994.

² Hiramatsu, H.; Yanagi, H.; Kamiya, T.; Ueda, K.; Hirano, M.; Hosono, H.; *Chem. Mater.* 2008, **20**, 326.

The Seebeck coefficient at a given temperature was determined by applying a temperature gradient, ΔT , across the sample and measuring the corresponding thermal voltage, ΔV . The slope of the line, $\Delta V/\Delta T$, was used to determine the Seebeck coefficient.

High-temperature electrical conductivity and Seebeck coefficient

The electrical conductivity σ and Seebeck coefficient S were measured by using an Ulvac-Riko ZEM 3 system from 300K to 825K under partial Helium pressure. According to the manufacturer, the uncertainty of the Seebeck coefficient and electrical conductivity is $\pm 7\%$.

Thermal conductivity

The thermal conductivity over the temperature range $100 \leq T/^{\circ}\text{C} \leq 400$, was measured using a commercial instrument (Anter FL3000), which applies the laser flash method, on hot-pressed pellets. This instrument determines both the thermal diffusivity (α) and the heat capacity (C_p) of the sample, and the thermal conductivity (κ) is calculated from the relationship:

$$\kappa = \alpha C_p \rho$$

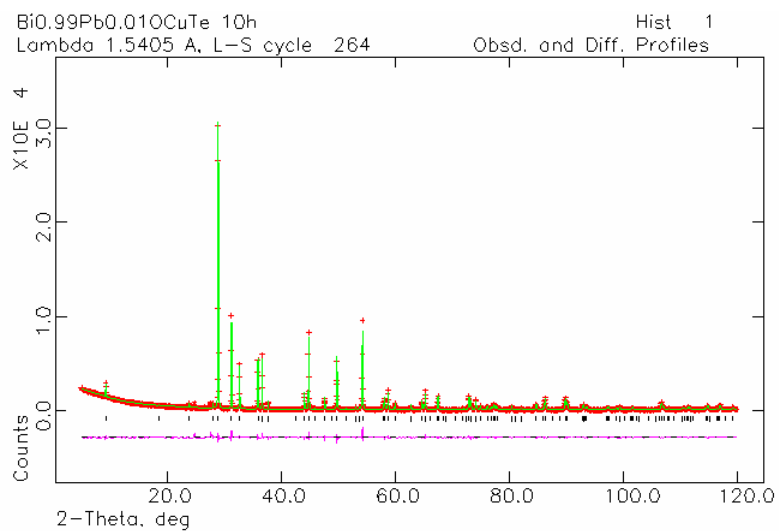
where ρ is the sample density. For the determination of the heat capacity, side-by-side testing of a reference material, Pyrocera™ 9606, was carried out.

According to the instrument manufacturer, the uncertainty of the thermal diffusivity measurements is $\pm 3\%$ and for heat capacity measurements is $\pm 6\%$. Considering the uncertainties of α , C_p and ρ , we estimate that the overall uncertainty of the thermal conductivity will be around $\pm 7\%$.

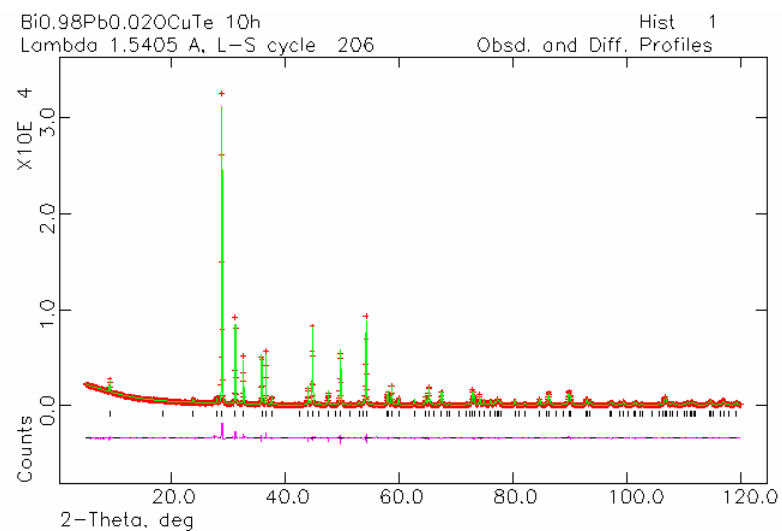
We estimate that the combined uncertainty for all measurements used for the determination of ZT is *ca.* 15%.

2. Rietveld refinements and powder X-ray diffraction analysis

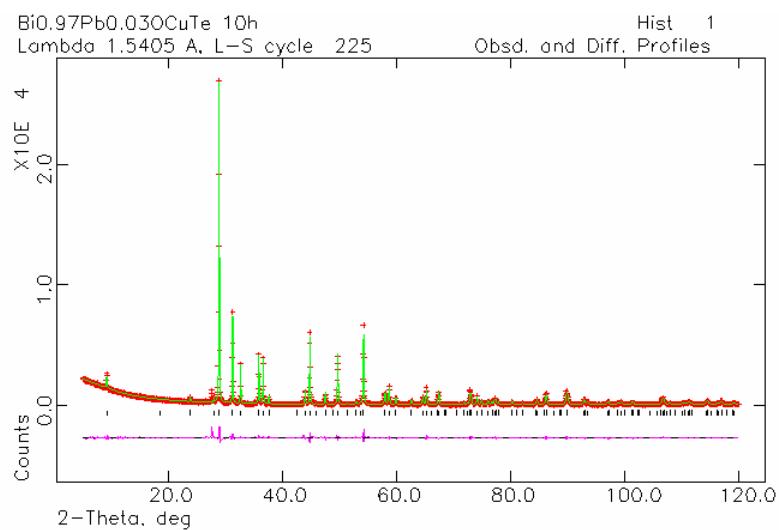
(a)



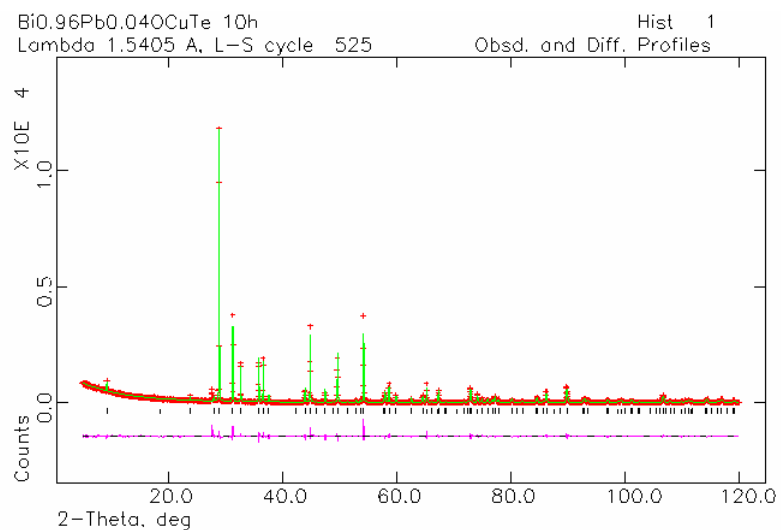
(b)



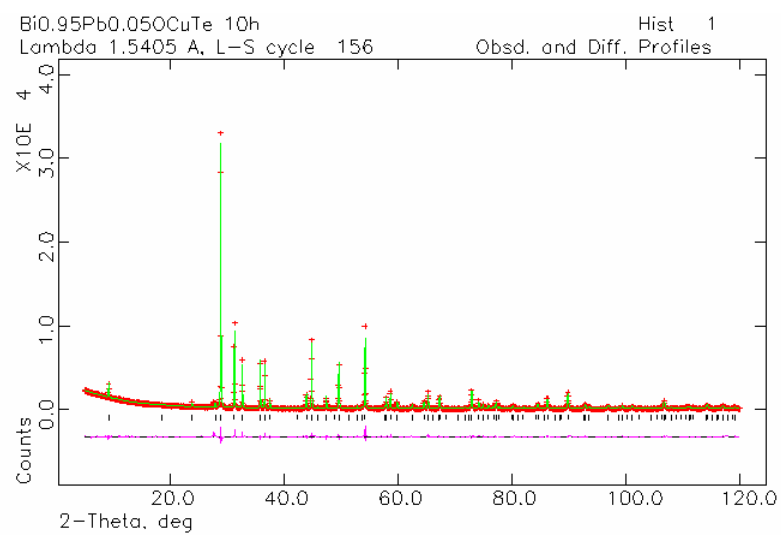
(c)



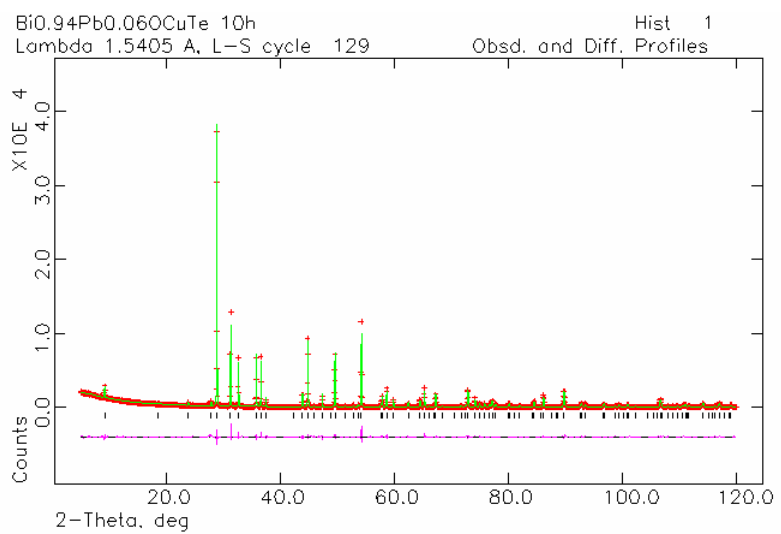
(d)



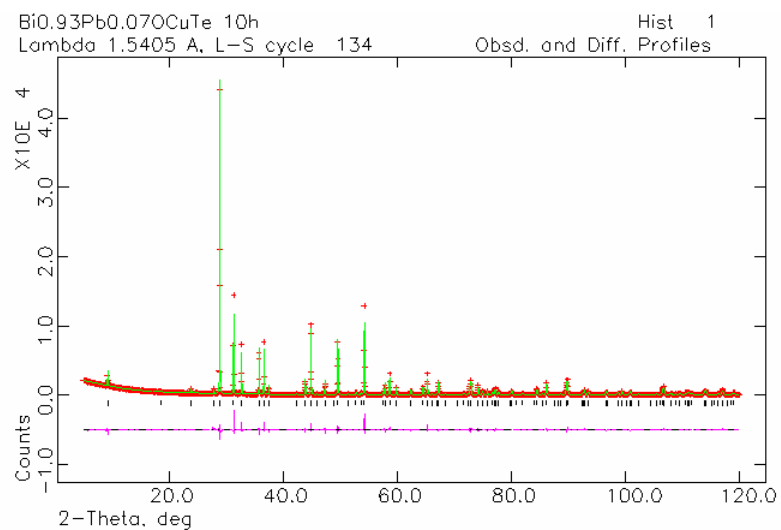
(e)



(f)



(g)



(h)

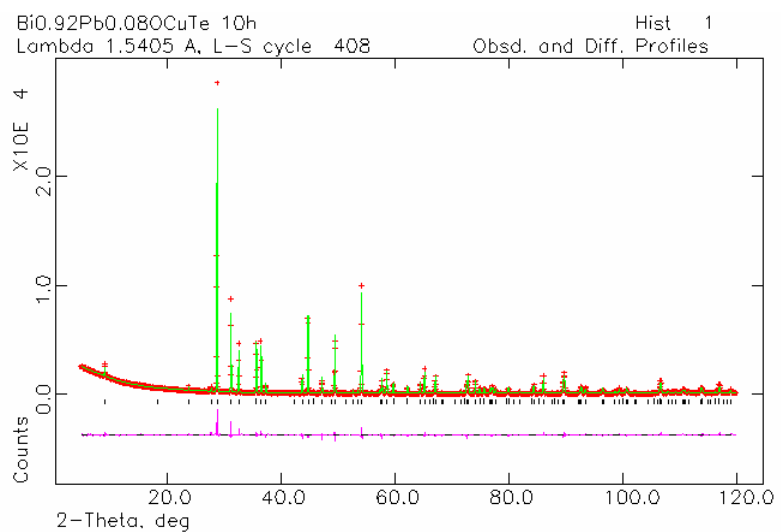


Figure S1. Rietveld refinements using power diffraction data for Bi_{1-x}Pb_xOCuTe ($0.01 \leq x \leq 0.08$).

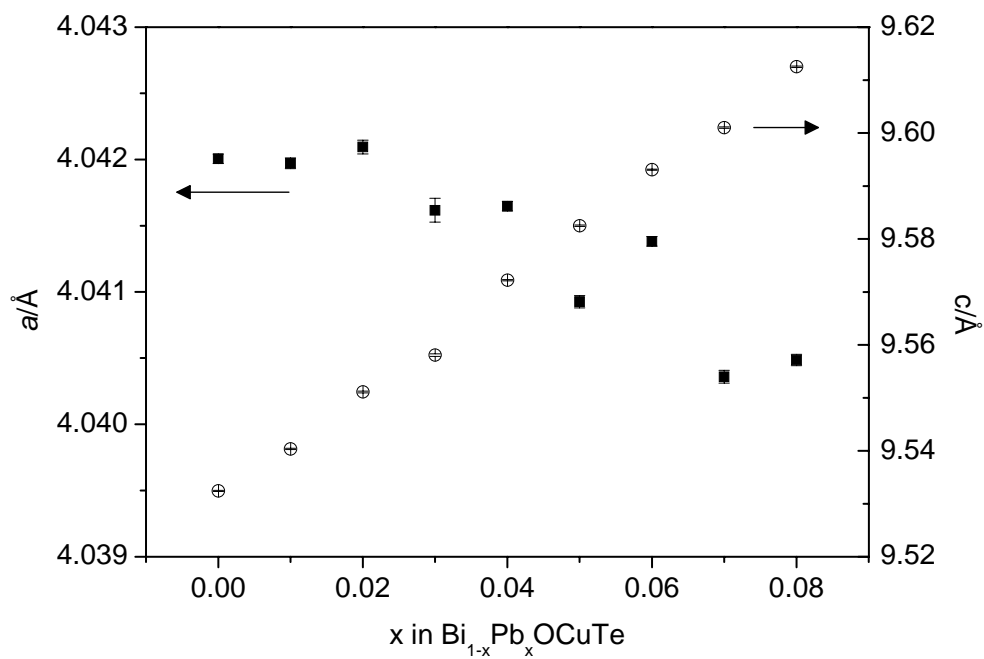


Figure S2. Lattice parameters for $\text{Bi}_{1-x}\text{Pb}_x\text{OCuTe}$ ($0 \leq x \leq 0.08$).

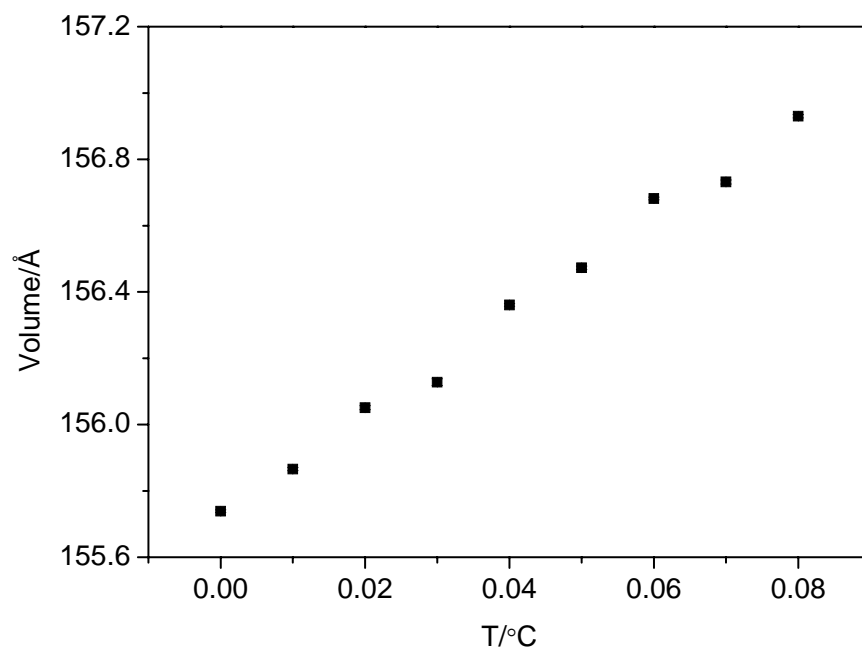


Figure S3. Unit cell volume for $\text{Bi}_{1-x}\text{Pb}_x\text{OCuTe}$ ($0 \leq x \leq 0.08$)

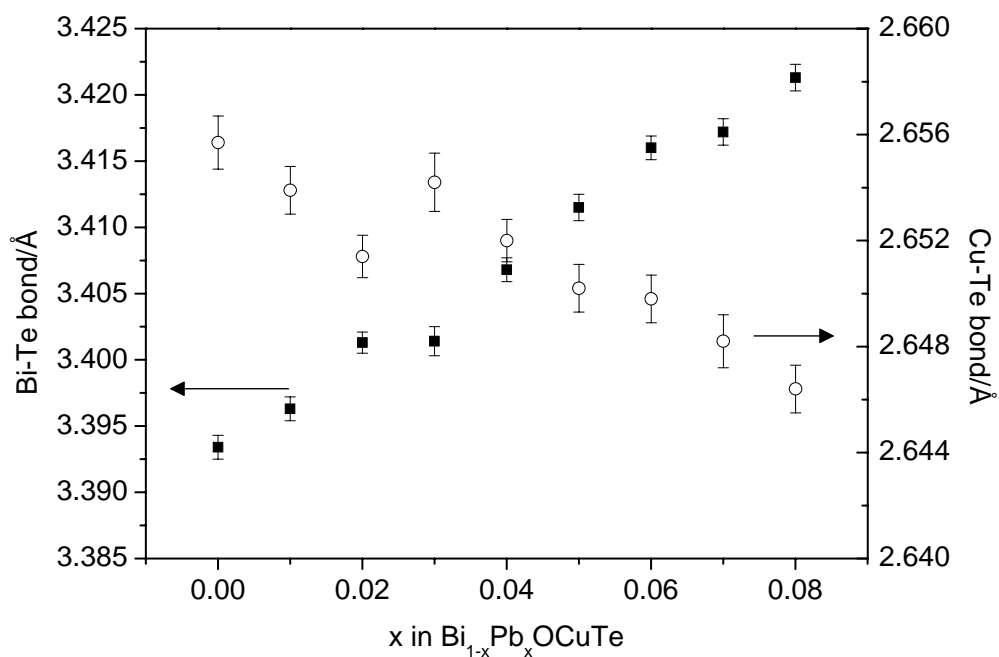


Figure S4. Bi-Te and Cu-Te bond lengths for $\text{Bi}_{1-x}\text{Pb}_x\text{OCuTe}$ ($0 \leq x \leq 0.08$).

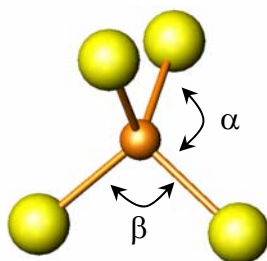
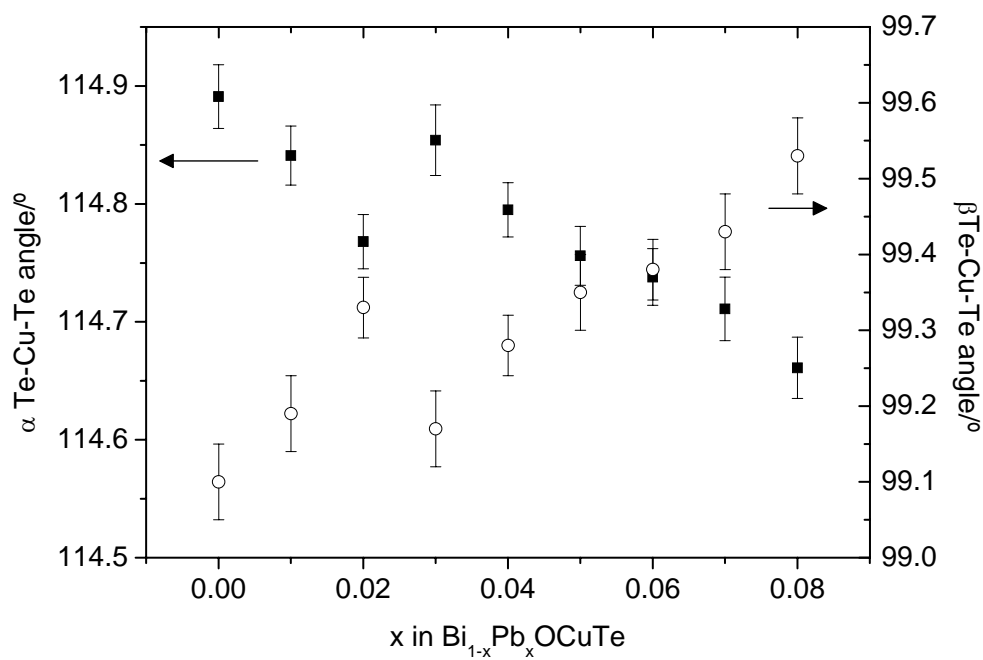


Figure S5. Te-Cu-Te bond angles for $\text{Bi}_{1-x}\text{Pb}_x\text{OCuTe}$ ($0 \leq x \leq 0.08$).

Table S1. Final refined parameters for Bi_{1-x}Pb_xOCuTe (0 ≤ x ≤ 0.08). Site occupancy factors for Bi and Pb were fixed at the stoichiometric composition.

		x in Bi _{1-x} Pb _x OCuTe								
		0.0	0.01	0.02	0.03	0.04	0.05	0.06	0.07	0.08
	<i>a</i> /Å	4.04200(4)	4.04197(4)	4.04209(5)	4.04162(9)	4.04164(4)	4.04093(5)	4.04138(4)	4.04036(5)	4.04049(4)
	<i>c</i> /Å	9.5324(1)	9.5403(1)	9.5511(2)	9.5580(2)	9.5722(1)	9.5825(1)	9.5931(1)	9.6010(1)	9.6125(1)
Bi/Pb ^a	<i>z</i>	0.1274(1)	0.1274(1)	0.1273(1)	0.1270(1)	0.1269(1)	0.1265(1)	0.1262(1)	0.1264(1)	0.1264(1)
	B/Å ²	0.50(2)	0.61(2)	1.17(2)	1.05(3)	1.01(4)	1.05(2)	1.02(2)	0.76(2)	0.86(2)
O ^b	B/Å ²	0.6(3)	0.4(3)	1.6(3)	1.0(4)	1.4(3)	1.3(3)	1.2(3)	0.9(4)	2.0(4)
Cu ^c	B/Å ²	1.02(8)	1.11(8)	1.85(8)	1.53(9)	1.49(8)	1.52(8)	1.47(8)	1.27(8)	1.54(8)
Te ^a	<i>z</i>	0.6808(2)	0.6803(1)	0.6797(1)	0.6800(2)	0.6794(1)	0.6790(1)	0.6786(1)	0.6783(2)	0.6778(2)
	B/Å ²	0.37(3)	0.53(4)	0.99(3)	0.90(4)	0.79(3)	0.82(3)	0.81(3)	0.56(4)	0.71(4)
R _{wp} /%		12.4	9.5	9.3	10.4	14.1	9.6	10.0	11.8	11.1

^aBi/Pb and Te on 2(*c*) (0,0,1/2); ^bO on 2(*a*) (3/4,1/4,0); ^cCu on 2(*b*) (3/4,1/4,1/2).

3. Physical properties

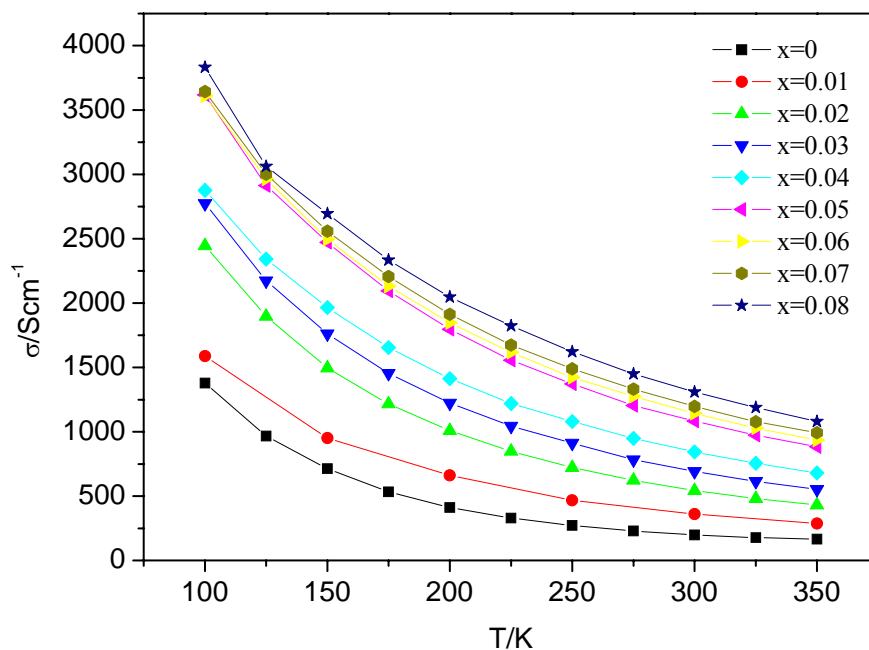


Figure S6. Electrical conductivity for $\text{Bi}_{1-x}\text{Pb}_x\text{OCuTe}$ ($0 \leq x \leq 0.08$) at low temperatures.

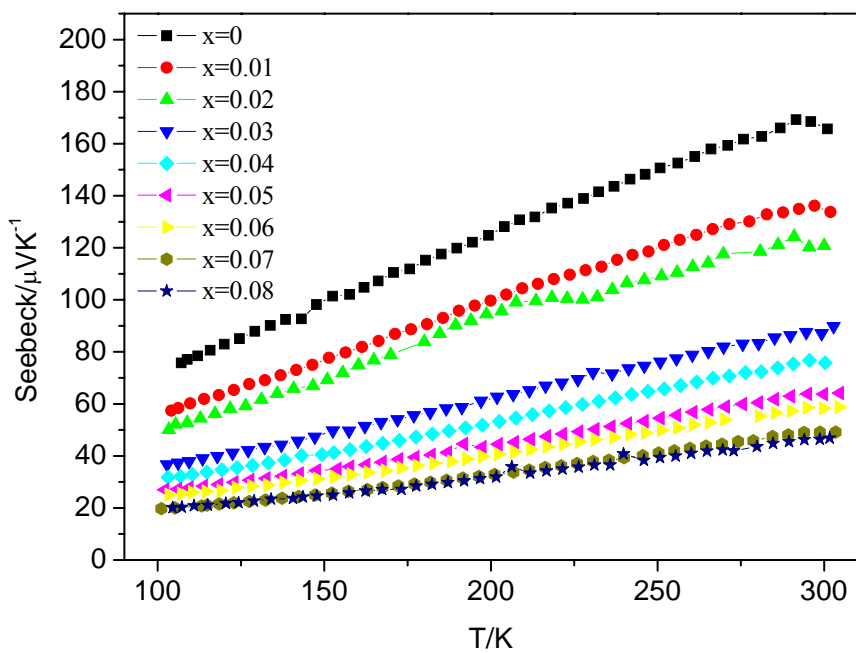


Figure S7. Seebeck coefficient for $\text{Bi}_{1-x}\text{Pb}_x\text{OCuTe}$ ($0 \leq x \leq 0.08$) at low temperatures.

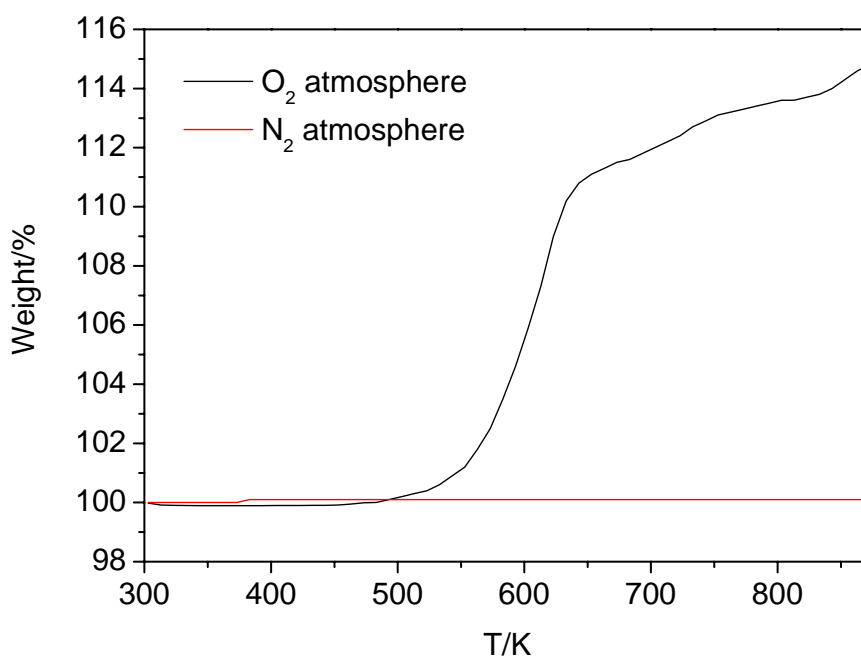


Figure S8. Thermogravimetric analysis of BiOCuTe under O₂ and N₂ atmospheres.

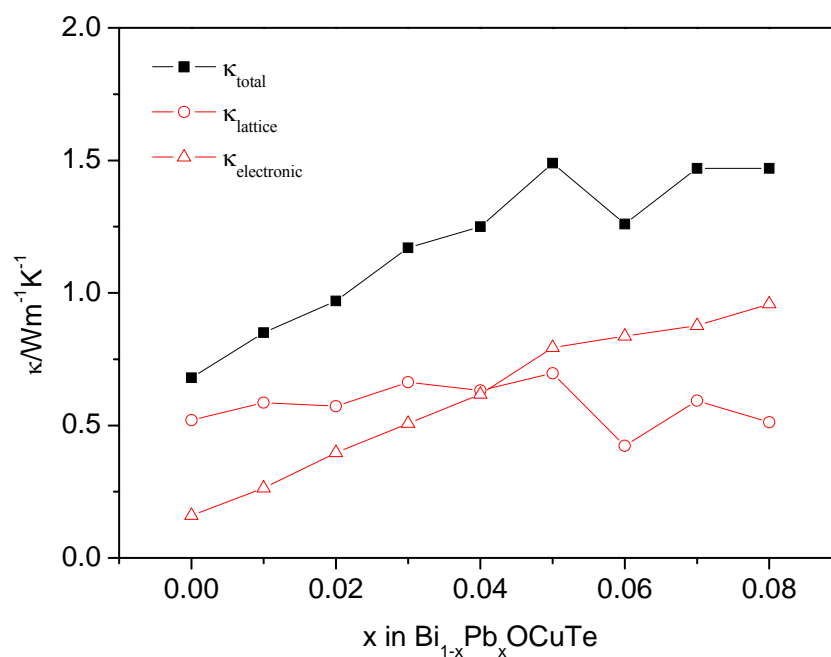


Figure S9. Estimated lattice and electronic thermal conductivities for Bi_{1-x}Pb_xOCuTe (0 ≤ x ≤ 0.08) at 373 K.